LU2020 First Announcement & Call For Paper

October 18-22, 2020

Nanjing, China

Organized by: Nanjing University of Science &Technology Sponsored by: The Acoustical Society of China The Acoustical Society of Jiangsu Jiangsu Optical Society Nanjing Photonics and Laser Engineering Society

http://lu2020.njust.edu.cn

We have the pleasure to invite you to the 7th International Symposium on Laser Ultrasonics and Advanced Sensing (LU2020) to be held in Nanjing, China, from 18 to 22 October, 2020.

The symposium was started in 2008 in order to provide a communication platform for researchers and technicians in the field of LU, dedicated to the latest scientific results, methodological and technological advancements, and the most relevant Ultrasonics. applications of Laser According to the tradition of LU symposia, researchers from academia and industry are invited to participate and exchange their knowledge on Laser Ultrasonics and Advanced sensing.

Symposium Topics

- **1.General Laser Ultrasonics**
- 2. Laser Ultrasonics for NDE&Industrial Applications
- 3. Ultrafast Laser Ultrasonics and Micro/Nanoscale

Measurements

Advanced Sensing and Instrumentation
Photoacoustic and Biomedical Applications

Publications

Abstracts of this conference will be published online by

MDPI. Full papers are encouraged to be summited to Applied Sciences from MDPI (ISSN 2076-3417; Applied Sciences-Basel recorded in Web of Science, Impact factor 2.217 in 2018), and will be published in a special issue "Applied Science: Laser Ultrasonics" after a regular peer review process.

applied sciences





Abstract Submission Information Requirements

To ensure a high-quality conference, only papers that present new original research and are written well in clear English will be accepted. All abstracts and manuscripts will be reviewed by the Program Committee.

Submission Method

1.Visit the conference website(<u>http://lu2020.njust.edu.cn/</u>), from the MENU, find "Abstract Submission" and click it.

2.In the ABSTRACT SUBMISSION details, click the linkage to open abstract submission website.3.Use an available e-mail address to register, then log in and submit your abstract.

Important

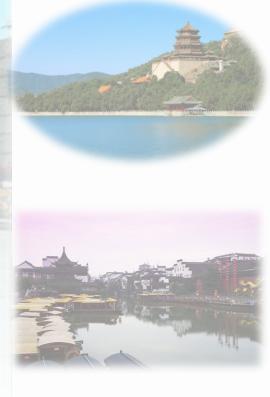
1. Deadline for the submission of abstracts is April 20, 2020

2. The abstracts should be prepared in accordance with the template (Download from http://lu2020.njust.edu.cn/). Abstracts are supposed to be written in English. Not more than one A4 page, including figures, table, formulas and references.

3. Please indicate whether an oral presentation or a poster is preferred and also indicate the scope of your presentation in your submission. The final decision regarding the presentation type, however, will be taken by the scientific committee.

4. After a review process by the scientific committee, authors will be notified of acceptance of their abstracts before **May 20, 2020**.





International Advisory Committee

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